

PRELIMINARY

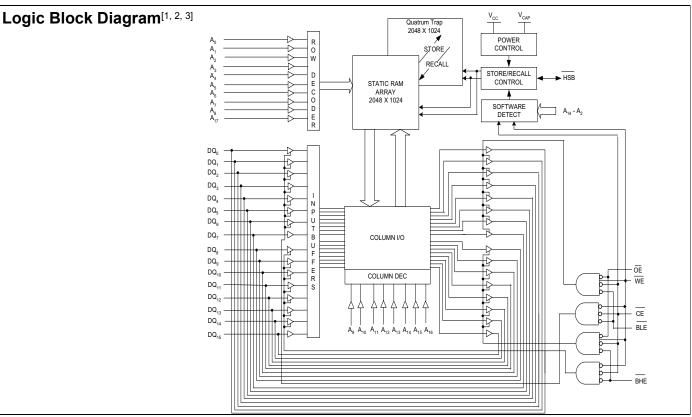
CY14B102L, CY14B102N 2 Mbit (256K x 8/128K x 16) nvSRAM

Features

- 20 ns, 25 ns, and 45 ns Access Times
- Internally organized as 256K x 8 (CY14B102L) or 128K x 16 (CY14B102N)
- Hands off Automatic STORE on power down with only a small Capacitor
- STORE to QuantumTrap[®] nonvolatile elements initiated by software, device pin, or AutoStore[®] on power down
- RECALL to SRAM initiated by software or power up
- Infinite Read, Write, and Recall Cycles
- 200,000 STORE cycles to QuantumTrap
- 20 year data retention
- Single 3V +20% to -10% operation
- Commercial, Industrial and Automotive Temperatures
- 48-ball FBGA and 44/54-pin TSOP II packages
- Pb-free and RoHS compliance

Functional Description

The Cypress CY14B102L/CY14B102N is a fast static RAM, with a nonvolatile element in each memory cell. The memory is organized as 256K bytes of 8 bits each or 128K words of 16 bits each. The embedded nonvolatile elements incorporate QuantumTrap technology, producing the world's most reliable nonvolatile memory. The SRAM provides infinite read and write cycles, while independent nonvolatile data resides in the highly reliable QuantumTrap cell. Data transfers from the SRAM to the nonvolatile elements (the STORE operation) takes place automatically at power down. On power up, data is restored to the SRAM (the RECALL operation) from the nonvolatile memory. Both the STORE and RECALL operations are also available under software control.



- Note
- Address A₀ A₁₇ for x8 configuration and Address A₀ A₁₆ for x16 configuration.
 <u>Data</u> DQ₀ DQ₇ for x8 configuration and Data DQ₀ DQ₁₅ for x16 configuration.
 BHE and BLE are applicable for x16 configuration only.

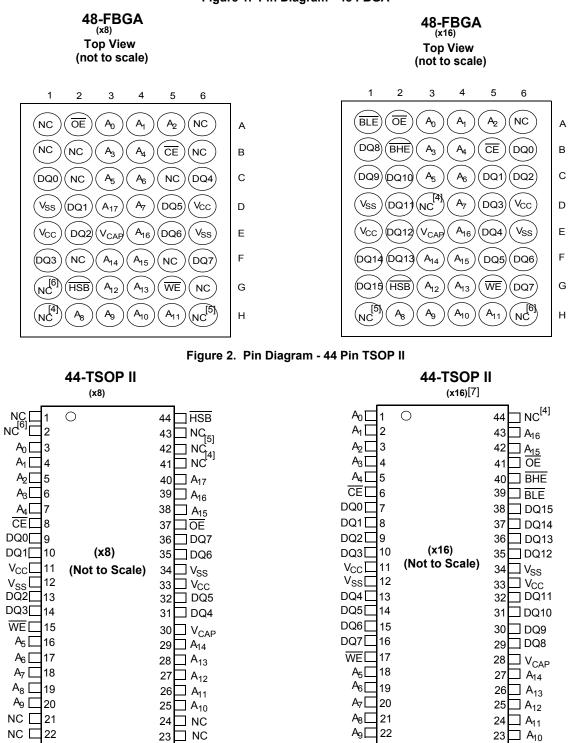
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San Jose, CA 95134-1709 408-943-2600 ٠ Revised November 10, 2008



Pinouts

Figure 1. Pin Diagram - 48 FBGA



Notes

- Address expansion for 4 Mbit. NC pin not connected to die. 4.
- Address expansion for 8 Mbit. NC pin not connected to die. 5.

Address expansion for 16 Mbit. NC pin not connected to die. HSB pin is not available in 44-TSOP II (x16) package. 6.

7.



Pinouts	(continued)
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Figure 3. Pin Diagram - 54 Pin TSOP II (x16)

$\begin{array}{c c c c c c c c c c c c c c c c c c c $	(x16) (Not to Scale)	$ \begin{array}{c c c c c c c c c c c c c c c c c c c $
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Pin Definitions

Pin Name	Ю Туре	Description
A ₀ – A ₁₇	Input	Address Inputs Used to Select one of the 262,144 bytes of the nvSRAM for x8 Configuration.
$A_0 - A_{16}$		Address Inputs Used to Select one of the 131,072 words of the nvSRAM for x16 Configuration.
$DQ_0 - DQ_7$	Input/Output	Bidirectional Data IO Lines for x8 Configuration. Used as input or output lines depending on operation.
DQ ₀ – DQ ₁₅		Bidirectional Data IO Lines for x16 Configuration. Used as input or output lines depending on operation.
WE	Input	Write Enable Input, Active LOW. When selected LOW, data on the IO pins is written to the specific address location.
CE	Input	Chip Enable Input, Active LOW. When LOW, selects the chip. When HIGH, deselects the chip.
OE	Input	Output Enable, Active LOW . The active LOW OE input enables the data output buffers during read cycles. IO pins are tri-stated on deasserting OE HIGH.
BHE	Input	Byte High Enable, Active LOW. Controls DQ ₁₅ - DQ ₈ .
BLE	Input	Byte Low Enable, Active LOW. Controls DQ ₇ - DQ ₀ .
V _{SS}	Ground	Ground for the Device. Must be connected to the ground of the system.
Vcc	Power Supply	Power Supply Inputs to the Device.
HSB ^[7]	Input/Output	Hardware Store Busy (HSB) . When LOW this output indicates that a hardware store is in progress. When pulled LOW external to the chip it initiates a nonvolatile STORE operation. A weak internal pull up resistor keeps this pin HIGH if not connected (connection optional). After each store operation HSB will be driven HIGH for short time with standard output high current.
V _{CAP}	Power Supply	AutoStore Capacitor. Supplies power to the nvSRAM during power loss to store data from SRAM to nonvolatile elements.
NC	No Connect	No Connect. This pin is not connected to the die.

PRELIMINARY



Device Operation

The CY14B102L/CY14B102N nvSRAM is made up of two functional components paired in the same physical cell. They are an SRAM memory cell and a nonvolatile QuantumTrap cell. The SRAM memory cell operates as a standard fast static RAM. Data in the SRAM is transferred to the nonvolatile cell (the STORE operation), or from the nonvolatile cell to the SRAM (the RECALL operation). Using this unique architecture, all cells are stored and recalled in parallel. During the STORE and RECALL operations, SRAM read and write operations are inhibited. The CY14B102L/CY14B102N supports infinite reads and writes similar to a typical SRAM. In addition, it provides infinite RECALL operations. See the "Truth Table For SRAM Operations" on page 15 for a complete description of read and write modes.

SRAM Read

The <u>CY14B102L/CY14B102N</u> performs a read cycle when \overline{CE} and \overline{OE} are LOW and WE and HSB are HIGH. The address specified on pins A₀₋₁₇ or A₀₋₁₆ determines which of the 262,144 data bytes or 131,072 words of 16 bits each are accessed. Byte enables (BHE, BLE) determine which bytes are enabled to the output, in the case of 16-bit words. When the read is initiated by an address transition, the outputs are valid after a delay of t_{AA} (read cycle 1). If the read is initiated by CE or OE, the outputs are valid at t_{ACE} or at t_{DOE}, whichever is later (read cycle 2). The data output repeatedly responds to address changes within the t_{AA} access time without the need for transitions on any control input_pins. <u>This</u> remains valid until another address change or until CE or OE is brought HIGH, or WE or HSB is brought LOW.

SRAM Write

A write cycle is performed when \overline{CE} and \overline{WE} are LOW and \overline{HSB} is HIGH. The address inputs must be stable before entering the write cycle and must remain stable until \overline{CE} or \overline{WE} goes HIGH at the end of the cycle. The data on the common IO pins DQ_{0-15} are written into the memory if the data is valid t_{SD} before the end of a WE controlled write or before the end of an \overline{CE} controlled write. The Byte Enable inputs (BHE, BLE) determine which bytes are written, in the case of 16-bit words. It is recommended that \overline{OE} be kept HIGH during the entire write cycle to avoid data bus contention on common IO lines. If \overline{OE} is left LOW, internal circuitry turns off the output buffers t_{HZWE} after \overline{WE} goes LOW.

AutoStore Operation

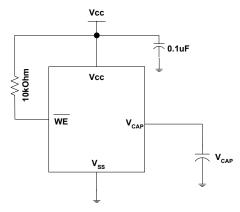
The CY14B102L/CY14B102N stores data to the nvSRAM using one of the following three storage operations: Hardware Store activated by HSB; Software Store activated by an address sequence; AutoStore on device power down. The AutoStore operation is a unique feature of QuantumTrap technology and is enabled by default on the CY14B102L/CY14B102N.

During a normal operation, the device draws current from V_{CC} to charge a capacitor connected to the V_{CAP} pin. This stored charge is used by the chip to perform a single STORE operation. If the voltage on the V_{CC} pin drops below V_{SWITCH} , the part automatically disconnects the V_{CAP} pin from V_{CC} . A STORE operation is initiated with power provided by the V_{CAP} capacitor.

Figure 4 shows the proper connection of the storage capacitor (V_{CAP}) for automatic store operation. Refer to DC Electrical Characteristics on page 7 for the size of V_{CAP}. The voltage on the V_{CAP} pin is driven to V_{CC} by a regulator on the chip. A pull up should be placed on WE to hold it inactive during power up. This pull up is only effective if the WE signal is tri-state during power up. Many MPUs tri-state their controls on power up. This should be verified when using the pull up. When the nvSRAM comes out of power-on-recall, the MPU must be active or the WE held inactive until the MPU comes out of reset.

To reduce unnecessary nonvolatile stores, AutoStore and hardware store operations are ignored unless at least one write operation has taken place since the most recent STORE or RECALL cycle. Software initiated STORE cycles are performed regardless of whether a write operation has taken place. The HSB signal is monitored by the system to detect if an AutoStore cycle is in progress.

Figure 4. AutoStore Mode



Hardware STORE Operation

The CY14B102L/CY14B102N provides the $\overline{\text{HSB}^{[7]}}$ pin to control and acknowledge the STORE operations. Use the HSB pin to request a hardware STORE cycle. When the HSB pin is driven LOW, the CY14B102L/CY14B102N conditionally initiates a STORE operation after t_{DELAY}. An actual STORE cycle only begins if a write to the SRAM <u>has</u> taken place since the last STORE or RECALL cycle. The HSB pin also acts as an open drain driver that is internally driven LOW to indicate a busy condition when the STORE (initiated by any means) is in progress.

SRAM read and write operations that are in progress when HSB is driven LOW by any means are given time to complete before the STORE operation is initiated. After HSB goes LOW, the CY14B102L/CY14B102N continues SRAM operations for t_{DELAY} . If a write is in progress when HSB is pulled LOW it is enabled a time, t_{DELAY} to complete. However, any SRAM write cycles requested after HSB goes LOW are inhibited until HSB returns HIGH. In case the write latch is not set, HSB will not be driven LOW by the CY14B102L/CY14B102L/CY14B102N but any SRAM read and write cycles are inhibited until HSB is returned HIGH by MPU or other external source.

During any STORE operation, regardless of how it is <u>initia</u>ted, the CY14B102L/CY14B102N continues to drive the HSB pin LOW, releasing it only when the STORE is complete. Upon



completion of the STORE operation the CY14B102L/CY14B102N remains disabled until the HSB pin returns HIGH. Leave the HSB unconnected if it is not used.

Hardware RECALL (Power Up)

During power up or after any low power condition (V_{CC}
 V_{SWITCH}), an internal RECALL request is latched. When V_{CC} again exceeds the sense voltage of V_{SWITCH} , a RECALL cycle is automatically initiated and takes t_{HRECALL} to complete. During this time, HSB will be driven LOW by the HSB driver.

Software STORE

Transfer data from the SRAM to the nonvolatile memory with a software address sequence. The CY14B102L/CY14B102N software STORE cycle is initiated by executing sequential CE controlled read cycles from six specific address locations in exact order. During the STORE cycle an erase of the previous nonvolatile data is first performed, followed by a program of the nonvolatile elements. After a STORE cycle is initiated, further input and output are disabled until the cycle is completed.

Because a sequence of READs from specific addresses is used for STORE initiation, it is important that no other read or write accesses intervene in the sequence, or the sequence is aborted and no STORE or RECALL takes place.

To initiate the software STORE cycle, the following read sequence must be performed.

- 1. Read Address 0x4E38 Valid READ
- 2. Read Address 0xB1C7 Valid READ
- 3. Read Address 0x83E0 Valid READ
- 4. Read Address 0x7C1F Valid READ
- 5. Read Address 0x703F Valid READ
- 6. Read Address 0x8FC0 Initiate STORE Cycle

Table 1. Mode Selection

Th<u>e</u> software sequence may be clocked with $\overline{\text{CE}}$ controlled reads or $\overline{\text{OE}}$ controlled reads. After the sixth address in the sequence is entered, the STORE cycle commences and the chip is disabled. HSB will be driven LOW. It is important to use read cycles and not write cycles in the sequence, although it is not necessary that $\overline{\text{OE}}$ be LOW for a valid sequence. After the t_{STORE} cycle time is fulfilled, the SRAM is activated again for the read and write operation.

Software RECALL

Transfer the data from the nonvolatile memory to the SRAM with a software address sequence. A software RECALL cycle is initiated with a sequence of read operations in a manner similar to the software STORE initiation. To initiate the RECALL cycle, the following sequence of CE controlled read operations must be performed.

- 1. Read Address 0x4E38 Valid READ
- 2. Read Address 0xB1C7 Valid READ
- 3. Read Address 0x83E0 Valid READ
- 4. Read Address 0x7C1F Valid READ
- 5. Read Address 0x703F Valid READ
- 6. Read Address 0x4C63 Initiate RECALL Cycle

Internally, RECALL is a two step procedure. First, the SRAM data is cleared; then, the nonvolatile information is transferred into the SRAM cells. After the t_{RECALL} cycle time, the SRAM is again ready for read and write operations. The RECALL operation does not alter the data in the nonvolatile elements.

CE	WE	OE, BHE, BLE ^[3]	A ₁₅ - A ₀ ^[8]	Mode	Ю	Power
Н	Х	Х	Х	Not Selected	Output High Z	Standby
L	Н	L	Х	Read SRAM	Output Data	Active
L	L	Х	Х	Write SRAM	Input Data	Active
L	Н	L	0x4E38 0xB1C7 0x83E0 0x7C1F 0x703F 0x8B45	Read SRAM Read SRAM Read SRAM Read SRAM Read SRAM AutoStore Disable	Output Data Output Data Output Data Output Data Output Data Output Data	Active ^[9, 10]

Notes

- While there are 18 address lines on the CY14B102L (17 address lines on the CY14B102N), only the 13 address lines (A₁₄ A₂) are used to control software modes. Rest of the address lines are don't care.
- 9. The six consecutive address locations must be in the order listed. WE must be HIGH during all six cycles to enable a nonvolatile cycle.
- 10. IO state depends on the state of OE, BHE, and BLE. The IO table shown assumes OE, BHE, and BLE LOW.



Table 1. Mode Selection (continued)

CE	WE	OE, BHE, BLE ^[3]	A ₁₅ - A ₀ ^[8]	Mode	Ю	Power
L	Н	L	0x4E38 0xB1C7 0x83E0 0x7C1F 0x703F 0x4B46	Read SRAM Read SRAM Read SRAM Read SRAM Read SRAM AutoStore Enable	Output Data Output Data Output Data Output Data Output Data Output Data	Active ^[9, 10]
L	Н	L	0x4E38 0xB1C7 0x83E0 0x7C1F 0x703F 0x8FC0	Read SRAM Read SRAM Read SRAM Read SRAM Read SRAM Nonvolatile Store	Output Data Output Data Output Data Output Data Output Data Output High Z	Active I _{CC2} ^[9, 10]
L	Н	L	0x4E38 0xB1C7 0x83E0 0x7C1F 0x703F 0x4C63	Read SRAM Read SRAM Read SRAM Read SRAM Read SRAM Nonvolatile Recall	Output Data Output Data Output Data Output Data Output Data Output High Z	Active ^[9, 10]

Preventing AutoStore

The AutoStore function is disabled by initiating an AutoStore disable sequence. A sequence of read operations is performed in a manner similar to the software STORE initiation. To initiate the AutoStore disable sequence, the following sequence of CE controlled read operations must be performed:

- 1. Read address 0x4E38 Valid READ
- 2. Read address 0xB1C7 Valid READ
- 3. Read address 0x83E0 Valid READ
- 4. Read address 0x7C1F Valid READ
- 5. Read address 0x703F Valid READ
- 6. Read address 0x8B45 AutoStore Disable

The AutoStore is re-enabled by initiating an AutoStore enable sequence. A sequence of read operations is performed in a manner similar to the software RECALL initiation. To initiate the AutoStore enable sequence, the following sequence of CE controlled read operations must be performed:

- 1. Read address 0x4E38 Valid READ
- 2. Read address 0xB1C7 Valid READ
- 3. Read address 0x83E0 Valid READ
- 4. Read address 0x7C1F Valid READ
- 5. Read address 0x703F Valid READ
- 6. Read address 0x4B46 AutoStore Enable

If the AutoStore function is disabled or re-enabled, a manual STORE operation (hardware or software) must be issued to save the AutoStore state through subsequent power down cycles. The part comes from the factory with AutoStore enabled.

Data Protection

The CY14B102L/CY14B102N protects data from corruption during low voltage conditions by inhibiting all externally initiated STORE and write operations. The low voltage condition is detected when $V_{CC} < V_{SWITCH}$. If the CY14B102L/CY14B102N is in a write mode (both CE and WE are LOW) at power up, after a RECALL or STOR<u>E</u>, the write is inhibited until the SRAM is enabled after t_{LZHSB} (HSB to output active). This protects against inadvertent writes during power up or brown out conditions.

Noise Considerations

Refer to CY application note AN1064.





Maximum Ratings

Exceeding maximum ratings may impair the useful life of the device. These user guidelines are not tested.

Storage Temperature65°C to +150°C
Maximum Accumulated Storage Time
At 150°C Ambient Temperature1000h
At 85°C Ambient Temperature 20 Years
Ambient Temperature with
Power Applied–55°C to +150°C
Supply Voltage on V_{CC} Relative to GND–0.5V to 4.1V
Voltage Applied to Outputs
in High-Z State–0.5V to V _{CC} + 0.5V
Input Voltage0.5V to Vcc + 0.5V
Transient Voltage (<20 ns) on
Any Pin to Ground Potential

DC Electrical Characteristics

Over the Operating Range $(V_{ab} = 2.7)/(to 3.6)/(to 3.$

Package Power Dissipation Capability (T _A = 25°C) 1.0W
Surface Mount Pb Soldering Temperature (3 Seconds)+260°C
DC Output Current (1 output at a time, 1s duration) 15 mA
Static Discharge Voltage > 2001V (per MIL-STD-883, Method 3015)
Latch Up Current > 200 mA

Operating Range

Range	Ambient Temperature	V _{cc}
Commercial	0°C to +70°C	2.7V to 3.6V
Industrial	-40°C to +85°C	2.7V to 3.6V
Automotive	-40°C to +125°C	2.7V to 3.6V

Parameter	Description	Test Conditions		Min	Max	Unit
I _{CC1}	Average V _{CC} Current	t _{RC} = 20 ns t _{RC} = 25 ns t _{RC} = 45 ns	Commercial		65 65 50	mA mA mA
		Values obtained without output loads (I _{OUT} = 0 mA)	Industrial		70 70 52	mA mA mA
		t _{RC} = 25 ns t _{RC} = 45 ns Values obtained without output loads (I _{OUT} = 0 mA)	Automotive		90 75	mA mA
I _{CC2}	Average V _{CC} Current during STORE	All Inputs Don't Care, V _{CC} = Max Average current for duration t _{STORE}			10	mA
I _{CC3} ^[11]	t _{RC} = 200 ns, 3V, 25°C typical	All I/P cycling at CMOS levels. Values obtained without output loads (I _{OUT} = 0 mA).			35	mA
I _{CC4}	Average V _{CAP} Current during AutoStore Cycle	All Inputs Don't Care, V _{CC} = Max Average current for duration t _{STORE}			5	mA
I _{SB}		$\overline{CE} \ge (V_{CC} - 0.2)$. All others $V_{IN} \le 0.2V$ or $\ge (V_{CC} - 0.2V)$. Standby current level after nonvolatile cycle is complete. Inputs are static. f = 0 MHz.			5	mA
I _{IX} ^[12]	Input Le <u>akag</u> e Current (except HSB)	V _{CC} = Max, V _{SS} ≤ V _{IN} ≤ V _{CC}		-1	+1	μA
	Inpu <u>t Lea</u> kage Current (for HSB)	V_{CC} = Max, $V_{SS} \le V_{IN} \le V_{CC}$		-100	+1	μA
I _{OZ}	Off-State Output Leakage Current	$V_{CC} = Max, V_{SS} \le V_{OUT} \le V_{CC}, CE \text{ or } OE \ge V_{IH} \text{ or } BI$ or WE $\le V_{IL}$	IE/BLE ≥ V _{IH}	-1	+1	μA
V _{IH}	Input HIGH Voltage			2.0	V _{CC} + 0.5	V
V _{IL}	Input LOW Voltage			$V_{ss} - 0.5$	0.8	V
V _{OH}	Output HIGH Voltage	I _{OUT} = –2 mA		2.4		V
V _{OL}	Output LOW Voltage	I _{OUT} = 4 mA			0.4	V
V _{CAP} ^[13]	Storage Capacitor	Between V _{CAP} pin and V _{SS} , 5V Rated		61	180	μF

Notes

Typical conditions for the active current shown on the DC Electrical characteristics are average values at 25°C (room temperature), and V_{CC} = 3V. Not 100% tested.
 The HSB pin has I_{OUT} = -2 uA for V_{OH} of 2.4V when both active HIGH and LOW drivers are disabled. When they are enabled standard V_{OH} and V_{OL} are valid. This parameter is characterized but not tested.
 V_{CAP} (Storage capacitor) nominal value is 68uF.



Data Retention and Endurance

Parameter	Description	Min	Unit
DATA _R	Data Retention	20	Years
NV _C	Nonvolatile STORE Operations	200	К

Capacitance

In the following table, the capacitance parameters are listed.^[14]

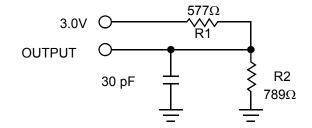
Parameter	Description	Test Conditions	Мах	Unit
C _{IN}	Input Capacitance	$T_A = 25^{\circ}C, f = 1 \text{ MHz},$	7	pF
C _{OUT}	Output Capacitance	$V_{CC} = 0$ to 3.0V	7	pF

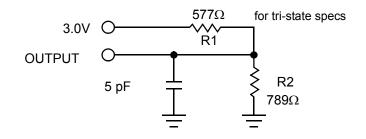
Thermal Resistance

In the following table, the thermal resistance parameters are listed. ^[14]

Parameter	Description	Test Conditions	48-FBGA	44-TSOP II	54-TSOP II	Unit
- JA	· /	Test conditions follow standard test methods and procedures for measuring thermal	28.82	31.11	30.73	°C/W
- 30	Thermal Resistance (Junction to Case)	impedance, in accordance with EIA/JESD51.	7.84	5.56	6.08	°C/W

Figure 5. AC Test Loads





AC Test Conditions

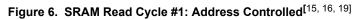
Input Pulse Levels	0V to 3V
Input Rise and Fall Times (10% - 90%)	<u><</u> 3 ns
Input and Output Timing Reference Levels	1.5V

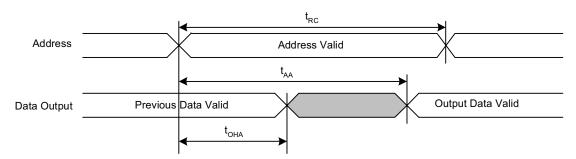


AC Switching Characteristics

Parar	neters		20	ns	25	ns	45	ns	
Cypress Parameters	Alt Parameters	Description	Min	Мах	Min	Max	Min	Мах	Unit
SRAM Read C	Cycle	•		•	•	•	•	•	•
t _{ACE}	t _{ACS}	Chip Enable Access Time		20		25		45	ns
t _{RC} ^[15]	t _{RC}	Read Cycle Time	20		25		45		ns
t _{AA} [16]	t _{AA}	Address Access Time		20		25		45	ns
t _{DOE}	t _{OE}	Output Enable to Data Valid		10		12		20	ns
t _{OHA} [16]	t _{OH}	Output Hold After Address Change	3		3		3		ns
t _{LZCE} ^[17]	t _{LZ}	Chip Enable to Output Active	3		3		3		ns
t _{HZCE} ^[17]	t _{HZ}	Chip Disable to Output Inactive		8		10		15	ns
t _{LZOE} ^[17]	t _{OLZ}	Output Enable to Output Active	0		0		0		ns
t _{HZOE} ^[17]	t _{OHZ}	Output Disable to Output Inactive		8		10		15	ns
t _{PU} ^[14]	t _{PA}	Chip Enable to Power Active	0		0		0		ns
t _{PD} ^[14]	t _{PS}	Chip Disable to Power Standby		20		25		45	ns
t _{DBE}	-	Byte Enable to Data Valid		10		12		20	ns
t _{LZBE}	-	Byte Enable to Output Active	0		0		0		ns
t _{HZBE}	-	Byte Disable to Output Inactive		8		10		15	ns
SRAM Write C	Cycle	· · · ·							
t _{WC}	t _{WC}	Write Cycle Time	20		25		45		ns
t _{PWE}	t _{WP}	Write Pulse Width	15		20		30		ns
t _{SCE}	t _{CW}	Chip Enable To End of Write	15		20		30		ns
t _{SD}	t _{DW}	Data Setup to End of Write	8		10		15		ns
t _{HD}	t _{DH}	Data Hold After End of Write	0		0		0		ns
t _{AW}	t _{AW}	Address Setup to End of Write	15		20		30		ns
t _{SA}	t _{AS}	Address Setup to Start of Write	0		0		0		ns
t _{нд}	t _{WR}	Address Hold After End of Write	0		0		0		ns
t _{HZWE} [17,18]	t _{WZ}	Write Enable to Output Disable		8		10		15	ns
t _{LZWE} ^[17]	t _{OW}	Output Active after End of Write	3		3		3		ns
t _{BW}	-	Byte Enable to End of Write	15		20		30		ns

Switching Waveforms





 Notes

 15. WE must be HIGH during SRAM read cycles.

 16. Device is continuously selected with CE, OE and BHE / BLE LOW.

 17. Measured ±200 mV from steady state output voltage.

 18. If WE is LOW when CE goes LOW, the outputs remain in the high impedance state.

 19. HSB must remain HIGH during READ and WRITE cycles.



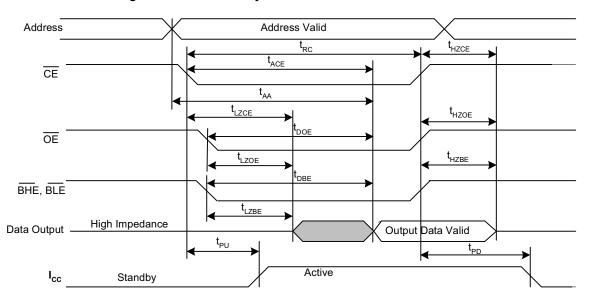
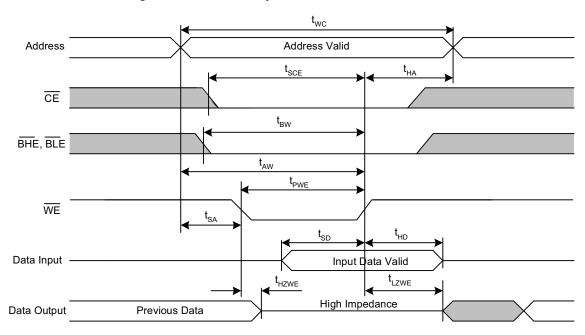


Figure 7. SRAM Read Cycle #2: $\overline{\text{CE}}$ and $\overline{\text{OE}}$ Controlled^[3, 15, 19]

Figure 8. SRAM Write Cycle #1: WE Controlled^[3, 18, 19, 20]





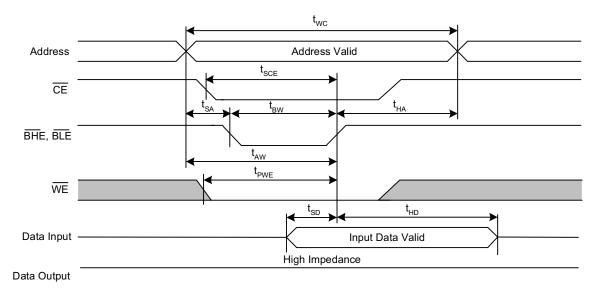


Figure 9. SRAM Write Cycle #2: CE Controlled^[3, 18, 19, 20]

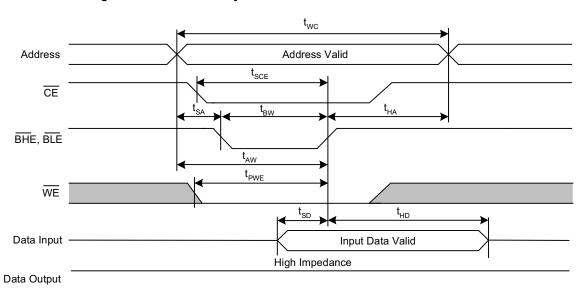


Figure 10. SRAM Write Cycle #3: BHE and BLE Controlled^[3, 18, 19, 20]



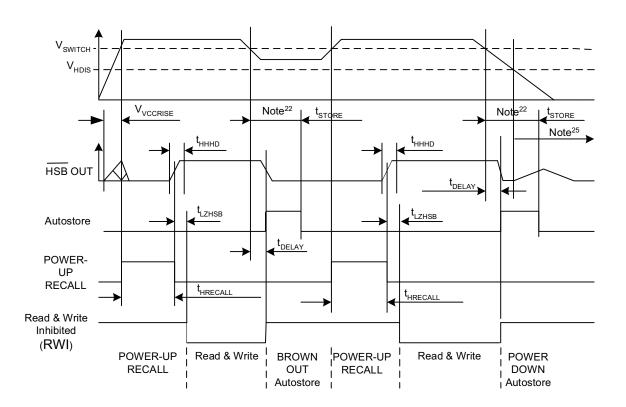


AutoStore/Power Up RECALL

Parameters	Description	20	ns	25	ns	45	45 ns	
	·	Min	Max	Min	Max	Min	Max	Unit
	Power Up RECALL Duration		20		20		20	ms
OTOTAL	STORE Cycle Duration		8		8		8	ms
t _{DELAY} ^[23]	Time Allowed to Complete SRAM Cycle		20		25		25	ns
V _{SWITCH}	Low Voltage Trigger Level		2.65		2.65		2.65	V
t _{VCCRISE}	VCC Rise Time	150		150		150		μS
V _{HDIS} ^[14]	HSB Output Driver Disable Voltage		1.9		1.9		1.9	V
t _{LZHSB}	HSB To Output Active Time		5		5		5	μS
t _{HHHD}	HSB High Active Time		500		500		500	ns

Switching Waveforms





Notes

21. t_{HRECALL} starts from the time V_{CC} rises above V_{SWITCH}.
 22. If an SRAM write has not taken place since the last nonvolatile cycle, no AutoStore or Hardware Store takes place.

23. On a Hardware STORE, Software Store / Recall, AutoStore Enable / Disable and AutoStore initiation, SRAM operation continues to be enabled for time t_{DELAY}.

- Read and Write cycles are ignored during STORE, RECALL, and while VCC is below V_{SWITCH}.
 HSB pin is driven HIGH to VCC only by internal 100kOhm resistor, HSB driver is disabled.





Software Controlled STORE/RECALL Cycle

In the following table, the software controlled STORE/RECALL cycle parameters are listed.^[26, 27]

Parameters	Description	20	ns	25	ns	45 ns		Unit
Farameters	Description	Min	Max	Min	Max	Min	Max	Unit
t _{RC}	STORE/RECALL Initiation Cycle Time	20		25		45		ns
t _{SA}	Address Setup Time	0		0		0		ns
t _{CW}	Clock Pulse Width	15		20		30		ns
t _{HA}	Address Hold Time	0		0		0		ns
t _{RECALL}	RECALL Duration		200		200		200	μS

Switching Waveforms

Figure 12. CE and OE Controlled Software STORE/RECALL Cycle^[27]

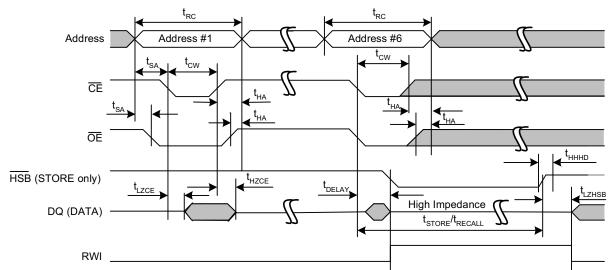
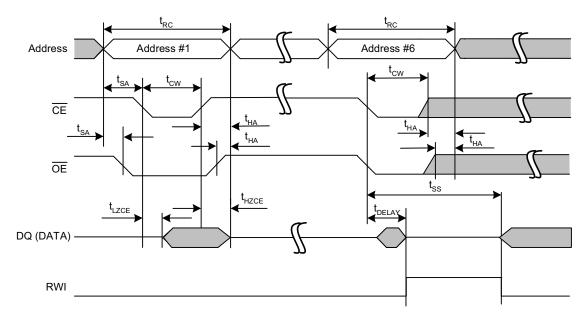


Figure 13. Autostore Enable/Disable Cycle



Notes

26. The software sequence is clocked with \overline{CE} controlled or \overline{OE} controlled reads.

27. The six consecutive addresses must be read in the order listed in Table 1 on page 5. WE must be HIGH during all six consecutive cycles.

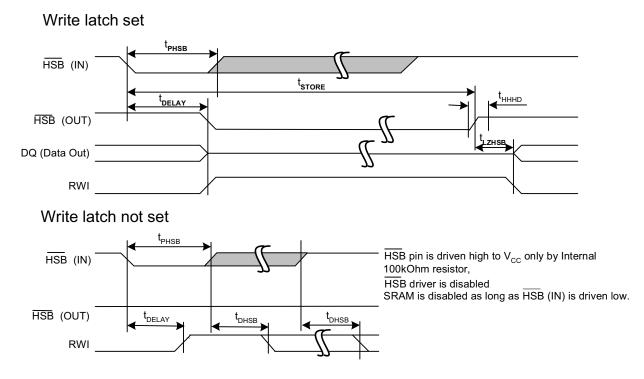


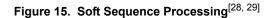
Hardware STORE Cycle

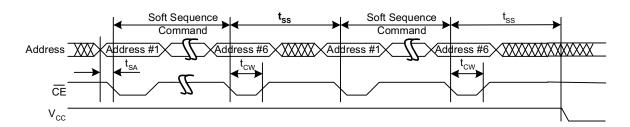
Parameters	Description	20	20 ns		25 ns		45 ns	
Farameters	Description	Min	Мах	Min	Мах	Min	Мах	Unit
t _{DHSB}	HSB To Output Active Time when write latch not set		20		25		25	ns
t _{PHSB}	Hardware STORE Pulse Width	15		15		15		ns
t _{SS} ^[28, 29]	Soft Sequence Processing Time		100		100		100	μS

Switching Waveforms

Figure 14. Hardware STORE Cycle^[22]







Notes

28. This is the amount of time it takes to take action on a soft sequence command. Vcc power must remain HIGH to effectively register command. 29. Commands such as STORE and RECALL lock out IO until operation is complete which further increases this time. See the specific command. PRELIMINARY



Truth Table For SRAM Operations

HSB should remain HIGH for SRAM Operations.

For x8 Configuration

CE	WE	OE	Inputs/Outputs ^[2]	Mode	Power
Н	Х	Х	High Z	Deselect/Power down	Standby
L	Н	L	Data Out (DQ ₀ –DQ ₇);	Read	Active
L	Н	Н	High Z	Output Disabled	Active
L	L	Х	Data in (DQ ₀ –DQ ₇);	Write	Active

For x16 Configuration

CE	WE	OE	BHE	BLE	Inputs/Outputs ^[2]	Mode	Power
Н	Х	Х	Х	Х	High-Z	Deselect/Power down	Standby
L	Х	Х	Н	Н	High-Z	Output Disabled	Active
L	Н	L	L	L	Data Out (DQ ₀ –DQ ₁₅)	Read	Active
L	Н	L	Н	L	Data Out (DQ ₀ –DQ ₇); DQ ₈ –DQ ₁₅ in High-Z	Read	Active
L	Н	L	L	Н	Data Out (DQ ₈ –DQ ₁₅); DQ ₀ –DQ ₇ in High-Z	Read	Active
L	Н	Н	L	L	High-Z	Output Disabled	Active
L	Н	Н	Н	L	High-Z	Output Disabled	Active
L	Н	Н	L	Н	High-Z	Output Disabled	Active
L	L	Х	L	L	Data In (DQ ₀ –DQ ₁₅)	Write	Active
L	L	х	Н	L	Data In (DQ ₀ –DQ ₇); DQ ₈ –DQ ₁₅ in High-Z	Write	Active
L	L	Х	L	Н	Data In (DQ ₈ –DQ ₁₅); DQ ₀ –DQ ₇ in High-Z	Write	Active



Ordering Information

Speed (ns)	Ordering Code	Package Diagram	Package Type	Operating Range
20	CY14B102L-ZS20XCT	51-85087	44-pin TSOP II	Commercial
	CY14B102L-ZS20XIT	51-85087	44-pin TSOP II	Industrial
	CY14B102L-ZS20XI	51-85087	44-pin TSOP II	
	CY14B102L-ZS20XAT	51-85087	44-pin TSOP II	Automotive
	CY14B102L-BA20XCT	51-85128	48-ball FBGA	Commercial
	CY14B102L-BA20XIT	51-85128	48-ball FBGA	Industrial
	CY14B102L-BA20XI	51-85128	48-ball FBGA	
	CY14B102L-BA20XAT	51-85128	48-ball FBGA	Automotivel
	CY14B102L-ZSP20XCT	51-85160	54-pin TSOP II	Commercial
	CY14B102L-ZSP20XIT	51-85160	54-pin TSOP II	Industrial
	CY14B102L-ZSP20XI	51-85160	54-pin TSOP II	
	CY14B102L-ZSP20XAT	51-85160	54-pin TSOP II	Automotive
	CY14B102N-ZS20XCT	51-85087	44-pin TSOP II	Commercial
	CY14B102N-ZS20XIT	51-85087	44-pin TSOP II	Industrial
	CY14B102N-ZS20XI	51-85087	44-pin TSOP II	
	CY14B102N-ZS20XAT	51-85087	44-pin TSOP II	Automotive
	CY14B102N-BA20XCT	51-85128	48-ball FBGA	Commercial
	CY14B102N-BA20XIT	51-85128	48-ball FBGA	Industrial
	CY14B102N-BA20XI	51-85128	48-ball FBGA	
	CY14B102N-BA20XAT	51-85128	48-ball FBGA	Automotive
	CY14B102N-ZSP20XCT	51-85160	54-pin TSOP II	Commercial
	CY14B102N-ZSP20XIT	51-85160	54-pin TSOP II	Industrial
	CY14B102N-ZSP20XI	51-85160	54-pin TSOP II	
	CY14B102N-ZSP20XAT	51-85160	54-pin TSOP II	Automotive





Ordering Information (continued)

Speed (ns)	Ordering Code	Package Diagram	Package Type	Operating Range
25	CY14B102L-ZS25XCT	51-85087	44-pin TSOP II	Commercial
	CY14B102L-ZS25XIT	51-85087	44-pin TSOP II	Industrial
	CY14B102L-ZS25XI	51-85087	44-pin TSOP II	
	CY14B102L-ZS25XAT	51-85087	44-pin TSOP II	Automotive
	CY14B102N-BA25XCT	51-85128	48-ball FBGA	Commercial
	CY14B102L-BA25XIT	51-85128	48-ball FBGA	Industrial
	CY14B102L-BA25XI	51-85128	48-ball FBGA	
	CY14B102N-BA25XAT	51-85128	48-ball FBGA	Automotive
	CY14B102L-ZSP25XCT	51-85160	54-pin TSOP II	Commercial
	CY14B102L-ZSP25XIT	51-85160	54-pin TSOP II	Industrial
	CY14B102L-ZSP25XI	51-85160	54-pin TSOP II	
	CY14B102L-ZSP25XAT	51-85160	54-pin TSOP II	Automotive
	CY14B102N-ZS25XCT	51-85087	44-pin TSOP II	Commercial
	CY14B102N-ZS25XIT	51-85087	44-pin TSOP II	Industrial
	CY14B102N-ZS25XI	51-85087	44-pin TSOP II	
	CY14B102N-ZS25XAT	51-85087	44-pin TSOP II	Automotive
	CY14B102N-BA25XCT	51-85128	48-ball FBGA	Commercial
	CY14B102N-BA25XIT	51-85128	48-ball FBGA	Industrial
	CY14B102N-BA25XI	51-85128	48-ball FBGA	
	CY14B102N-BA25XAT	51-85128	48-ball FBGAI	Automotive
	CY14B102N-ZSP25XCT	51-85160	54-pin TSOP II	Commercial
	CY14B102N-ZSP25XIT	51-85160	54-pin TSOP II	Industrial
	CY14B102N-ZSP25XI	51-85160	54-pin TSOP II	
	CY14B102N-ZSP25XAT	51-85160	54-pin TSOP II	Automotive

PRELIMINARY



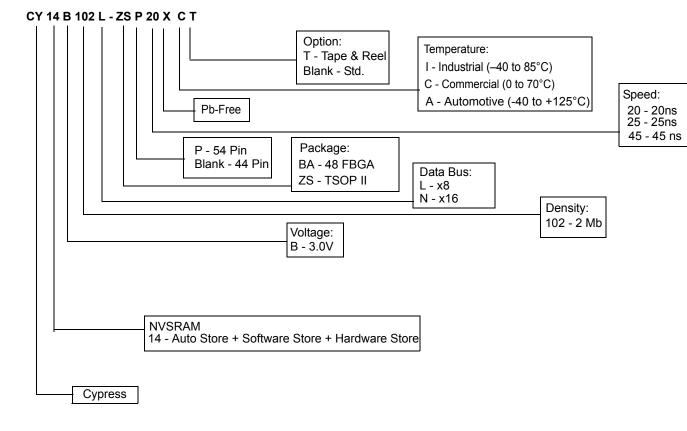
Ordering Information (continued)

Speed (ns)	Ordering Code	Package Diagram	Package Type	Operating Range
45	CY14B102L-ZS45XCT	51-85087	44-pin TSOP II	Commercial
	CY14B102L-ZS45XIT	51-85087	44-pin TSOP II	Industrial
	CY14B102L-ZS45XI	51-85087	44-pin TSOP II	
	CY14B102L-ZS45XAT	51-85087	44-pin TSOP II	Automotive
	CY14B102L-BA45XCT	51-85128	48-ball FBGA	Commercial
	CY14B102L-BA45XIT	51-85128	48-ball FBGA	Industrial
	CY14B102L-BA45XI	51-85128	48-ball FBGA	
	CY14B102L-BA45XAT	51-85128	48-ball FBGA	Automotive
	CY14B102L-ZSP45XCT	51-85160	54-pin TSOP II	Commercial
	CY14B102L-ZSP45XIT	51-85160	54-pin TSOP II	Industrial
	CY14B102L-ZSP45XI	51-85160	54-pin TSOP II	
	CY14B102L-ZSP45XAT	51-85160	54-pin TSOP II	Automotive
	CY14B102N-ZS45XCT	51-85087	44-pin TSOP II	Commercial
	CY14B102N-ZS45XIT	51-85087	44-pin TSOP II	Industrial
	CY14B102N-ZS45XI	51-85087	44-pin TSOP II	
	CY14B102N-ZS45XAT	51-85087	44-pin TSOP II	Automotive
	CY14B102N-BA45XCT	51-85128	48-ball FBGA	Commercial
	CY14B102N-BA45XIT	51-85128	48-ball FBGA	Industrial
	CY14B102N-BA45XI	51-85128	48-ball FBGA	
	CY14B102N-BA45XAT	51-85128	48-ball FBGA	Automotive
	CY14B102N-ZSP45XCT	51-85160	54-pin TSOP II	Commercial
	CY14B102N-ZSP45XIT	51-85160	54-pin TSOP II	Industrial
	CY14B102N-ZSP45XI	51-85160	54-pin TSOP II	
	CY14B102N-ZSP45XAT	51-85160	54-pin TSOP II	Automotive

All parts are Pb-free. The above table contains Preliminary information. Please contact your local Cypress sales representative for availability of these parts.



Part Numbering Nomenclature

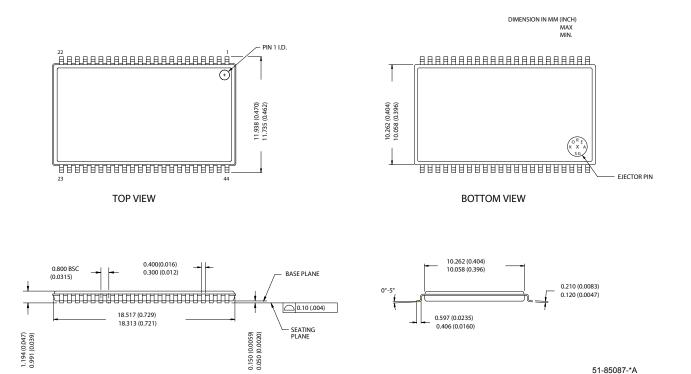






Package Diagrams

Figure 16. 44-Pin TSOP II (51-85087)

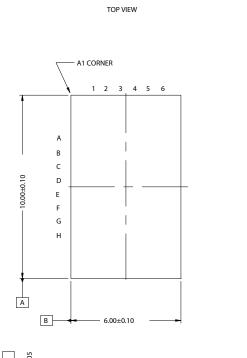


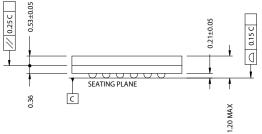
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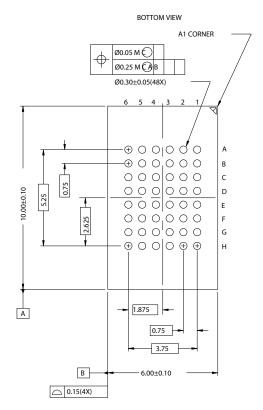


Package Diagrams (continued)







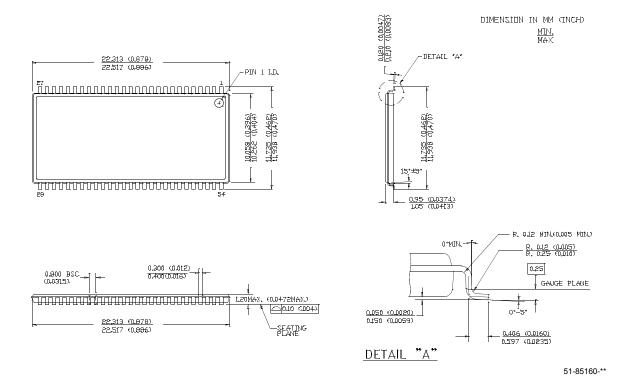


51-85128-*D



Package Diagrams (continued)

Figure 18. 54-Pin TSOP II (51-85160)





Document History Page

		CY14B102L/CY per: 001-45754	14B102N 2 Mbit (2	56K x 8/128K x 16) nvSRAM
Rev.	ECN No.	Submission Date	Orig. of Change	Description of Change
**	2470086	GVCH		New Data Sheet
*A	2522209	GVCH/AESA	06/27/2008	Added Automotive temperature Range and 20 ns access speed information in "Features". Added I_{CC1} for automotive temperature range. Added I_{CC1} for t_{RC} =20 ns for both industrial and Commercial temperature Grade. Updated Thermal resistance values for 48-FBGA, 44-TSOP II and 54-TSOP II Packages. Added AC Switching Characteristics specs for 20 ns access speed. Added software controlled STORE/RECALL cycle specs for 20 ns access speed. Updated ordering information and part numbering nomenclature. Updated data sheet template.
*B	2606696	GVCH/PYRS	11/13/08	Removed 15 ns access speed Updated Logic block diagram Updated footnote 1 Added footnote 2 and 7 Pin definition: Updated WE, HSB and NC pin description Page 4: Updated SRAM READ, SRAM WRITE, Autostore operation descrip- tion Page 4: Updated Hardware store operation Page 5: Hardware RECALL (Power-up) description Page 6: updated Data protection description Maximum Ratings: Added Max. Accumulated storage time Changed I _{CC2} from 6mA to 10mA Changed I _{CC4} from 6mA to 5mA Changed I _{CC4} from 6mA to 5mA Updated footnote 11and 12 Added footnote 13 Added Data retention and Endurance Table Updated Input Rise and Fall time in AC test Conditions Referenced footnote 16 to t _{OHA} parameter Updated All switching waveforms Added Figure 10 (SRAM WRITE CYCLE:BHE and BLE controlled) Changed t _{SELAY} to 20ns, 25ns, 25ns for 20ns, 25ns, 45ns part respectively Changed t _{SELAY} to 20ns, 25ns, 25ns for 20ns, 25ns, 45ns part respectively Changed t _{GHAX} to t _{HA} Added footnote 25 Software controlled STORE/RECALL cycle table: Changed t _{AS} to t _{SA} Changed t _{GHAX} to t _{HA} Added t _{DHSB} parameter Updated t _{GHAX} to t _{HA} Added t _{DHSB} parameter Changed t _{GHAX} to t _{HA} Added t _{DHSB} parameter Changed t _{GHAX} to t _{HA} Added Truth table for SRAM operations Updated ordering information and part numbering nomenclature





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Page 24 of 24

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